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| Notice of References Cited | Application/Control No. 10/604,599 | Applicant(s)/Patent Under Reexamination HO ET AL | |
| | Examiner Po-Wei (Dennis) Chen | Art Unit 2676 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| | A | US-6,774,953 B2 | 08-2004 | Champion et al. | 348/651 |
| | B | US-6,654,026 B2 | 11-2003 | Lee, Jae Min | 345/600 |
| | C | US-6,621,497 B1 | 09-2003 | Sugiura et al. | 345/600 |
| | D | US-5,596,510 A | 01-1997 | Boenke, Mark | 358/523 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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